

Notice of References Cited	Application/Control No. 10/533,698		Applicant(s)/Patent Under Reexamination PILOTEK ET AL.	
	Examiner John Freeman		Art Unit 4174	Page 1 of 1

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*	C	US-4,856,857 A	08-1989	Takeuchi et al.	359/3
*	D	US-5,035,473 A	07-1991	Kuwayama et al.	359/13
*	E	US-6,112,388 A	09-2000	Kimoto et al.	29/17.3
*	F	US-6,157,489 A	12-2000	Bradley et al.	359/584
*	G	US-6,398,999 B1	06-2002	Josephy et al.	264/81
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.